## **Commercial Announcements**

#### **New Philips XRD Software**

The latest version of Philips Analytical's APD1700 X-ray diffraction software for DEC VAX and PDP computers incorporates an increased range of analytical modules and features to improve measurement performance and aid data interpretation.

This is the first XRD package to offer an outstanding operating convenience of a user interface based on windowing for the DEC VMS operating system.

In addition to automatic phase identification and quantitative determination, APD1700 now includes enhanced facilities for residual stress, texture, line profile (crystallite size/microstrain) and crystallographic analysis.

#### **Two New Modules**

Pattern treatment is based on a unique multipass search procedure – which ensures rapid, reliable detection of both sharp and broad peaks. A new profile fitting module to find hidden peaks and resolve overlapping lines adds further to the already powerful qualitative analysis capability.

Also newly introduced is an expanded graphics display module, including options for visual monitoring of intermediate data and three-dimensional presentation for easy comparison of multiple scans.

#### **Efficient Operation**

The complete JCPDS Powder Diffraction File may be supplied on magnetic disc or as the Philips Total Access Diffraction Database on CD-ROM. Pattern matching is speeded by the ability to create user-specific sub-files.

Running under the multi-user, multi-tasking VMS and RSX operating systems, APD1700 permits economical centralised control of multiple diffractometers – while operators can work simultaneously on program set-up, measurement and examination of results. Flexible software design enables users' own databases and special routines to be introduced, allowing easy adaptation to meet the most demanding research and routine needs.

For further information:

Philips Industrial & Electro-acoustic Systems Division I&E Press Office, Christa Horrocks, Building HKF 5600 MD Eindhoven, The Netherlands

Tel.: +31, 40, 788620, Telex 35000 phtc nl nlfevsi

FAX.: +31, 40, 785651

#### New D 5000 X-ray Diffractometer from Siemens

Siemens has just introduced a new X-ray powder diffractometer designed to provide improved performance and greater flexibility for polycrystalline diffraction.

Featuring a new, high resolution goniometer, the D 5000 X-ray Diffractometer operates in horizontal or vertical mode and can be converted quickly from Theta-Theta to Theta-2 Theta geometry. The system includes a 3.0 kW X-ray generator, a radiation safety enclosure and counting electronics. It can also be operated with a Siemens 18.0 kW rotating anode X-ray generator. To optimize the system for specific applications, it can be configured with:

- PC or MicroVAX host computer.
- Computer-controlled slit system for resolution selection and divergence control.
- Multi-position sample changer.
- Combined stress/texture attachment for psi or omega stress analysis and texture studies on the same sample.
- Solid-state or position sensitive detectors.
- Programmable rotating sample holder for scans or selected azimuthal positions.

The system includes complete support of JCPDS databases for phase characterization of polycrystalline samples. Other software available for the D 5000 supports 3-D texture plotting and calculation of orientation distribution functions, stress analysis, temperature studies and aluminum bath ratio analysis.

For more information in USA or Canada: Siemens Analytical X-Ray Instruments, Inc. 6300 Enterprise Lane Madison, WI 53719 TEL: (608) 276-3000 FAX: (608) 276-3015

For more information worldwide: Siemens AG Analytical Systems E 689 Postfach 21 12 62 Siemensallee 84 D-7500 Karlsruhe 21, West Germany

TEL: (0721) 5 95-42 95 Telex: 78255-69

FAX: (0721) 5 95-45 06

# **Supplier Source Directory**

#### X-Ray Diffraction Analysis Service

- Inorganic materials our specialty: refractories, abrasives, minerals, ceramics
- Qualitative and quantitative analysis
- · Powder camera technique for very small specimens
- · Average crystallite size
- Optical microscopy, including indentification of mineral forms, contaminants, etc. in various materials
- Identification of asbestos
- Other services include X-ray fluorescence, emission spectroscopy, wet chemical and sieve analysis

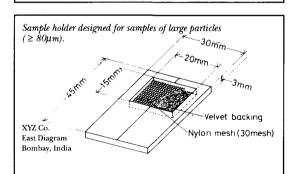
Washington Mills Electro Minerals Corporation
P. O. Box 423 • Niagara Falls, NY 14302
(716) 278-6796, – 6728

## **Advertising Announcements**

## **Supplier Source Directory**

John R. Doe
Professor of Chemistry and Geology
The Eastern University
Department of Chemistry
N.Y.C., N.Y.
Telephone . . . .
FAX . . . .

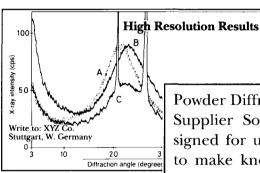
Consulting Services in XRD: Mineralogy



# Used Analytical X-ray Systems & Accessories Being Offered

Write to Receive Information
Name/Title
Institution/Company
Address
City
State
Country
Mail Code
XRD Company
Roentgen, Pennsylvania
Telephone . . . .

Examples of suggested styles for listings in the Supplier Source Directory.



# High Temperature

 $\begin{array}{lll} 551 & Ba_{0,8}Sr_{1,2}NaNb_5O_{15} \\ -- & BaSrKNb_5O_{15} \\ 547 & BaSrNa_{0,5}K_{0,5}Nb_5O_{15} \\ 150 & BaSrNaNb_5O_{15} \\ 225 & Ba_2LiTa_5O_{15} \\ 428 & Ba_2NaNb_{1,25}Ta_{3,75}O_{15} \\ Write to: \\ XYZ Company \\ West Blank, PA . . . . \\ Telephone . . . . \\ \end{array}$ 

#### X-ray Diffraction Softwar Personal Computers

XYZ Software Inc. Cheshire, U.K. Tel . . . . . FAX . . . .

announces the availability of the following software:

System 1: 1 System 2: 6

Forensics CD-ROM

PC

Powder Diffraction announces the Supplier Source Directory – designed for use by those who wish to make known their special services to the X-ray diffraction community. Rates are modest (no discounts for agencies), beginning at \$125.00 for one insertion (business card size).

For details please write or call Mary M. Rossi, Advertising Manager, JCPDS-ICDD at Swarthmore. (215-328-9403).

Examples of possible insertions are indicated on the Directory shown here (80% of actual size.)